

**Search Notes**

Application/Control No.

10/617,506

Examiner

Benjamin P. Geib

Applicant(s)/Patent under  
Reexamination

TAKAYAMA ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
717	140-146	2/2/2006	BPG

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	2/2/2006	BPG
IEEE Xplore Search	2/2/2006	BPG